

Nepremenné elektrické dvojvrstvové kondenzátory na použitie v elektrických a elektronických zariadeniach. Časť 1: Všeobecná špecifikácia.

STN EN 62391-1

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Fixed electric double-layer capacitors for use in electric and electronic equipment - Part 1: Generic specification

Táto norma obsahuje anglickú verziu európskej normy. This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 07/16

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# EUROPEAN STANDARD NORME EUROPÉENNE EUROPÄISCHE NORM

EN 62391-1

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#### **English Version**

Fixed electric double-layer capacitors for use in electric and electronic equipment - Part 1: Generic specification (IEC 62391-1:2015)

Condensateurs électriques fixes à double couche utilisés dans les équipements électriques et électroniques - Partie 1: Spécification générique (IEC 62391-1:2015)

Elektrische Doppelschichtkondensatoren zur Verwendung in elektrischen und elektronischen Geräten -Teil 1: Fachgrundspezifikation (IEC 62391-1:2015)

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CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

### **European foreword**

The text of document 40/2393/FDIS, future edition 2 of IEC 62391-1, prepared by IEC/TC 40 "Capacitors and resistors for electronic equipment" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62391-1:2016.

The following dates are fixed:

•	latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2016-08-27
•	latest date by which the national standards conflicting with the document have to be withdrawn	(dow)	2018-11-27

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-2-47:2005	NOTE	Harmonized as EN 60068-2-47:2005 (not modified).
IEC 60384-1:2008	NOTE	Harmonized as EN 60384-1:2009 (not modified).
IEC 61881-3:2012	NOTE	Harmonized as EN 61881-3:2012 (not modified).
IEC 62391-1:2006	NOTE	Harmonized as EN 62391-1:2006 1) (not modified).
IEC 62391-2:2006	NOTE	Harmonized as EN 62391-2:2006 (not modified).
IEC 62391-2-1:2006	NOTE	Harmonized as EN 62391-2-1:2006 (not modified).
IEC 62576:2009	NOTE	Harmonized as EN 62576:2010 (not modified).
ISO 80000-1:2009	NOTE	Harmonized as EN ISO 80000-1:2013 (not modified).

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<sup>&</sup>lt;sup>1)</sup> Superseded by EN 62391-1:2015 (IEC 62391-1:2015).

# Annex ZA

(normative)

# Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: <a href="https://www.cenelec.eu">www.cenelec.eu</a>

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60027	series	Letter symbols to be used in electrical technology	EN 60027	series
IEC 60050	series	International Electrotechnical Vocabulary	-	-
IEC 60062	-	Marking codes for resistors and capacitors	EN 60062	-
IEC 60063	-	Preferred number series for resistors and capacitors	EN 60063	-
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-1	2007	Environmental testing - Part 2-1: Tests - Test A: Cold	EN 60068-2-1	2007
IEC 60068-2-2	2007	Environmental testing - Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	2007
IEC 60068-2-6	2007	Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	2008
IEC 60068-2-14	2009	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	2009
IEC 60068-2-20	2008	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	2008
IEC 60068-2-21	2006	Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21	2006
IEC 60068-2-45	1980	Basic environmental testing procedures - Part 2-45: Tests - Test XA and guidance:	EN 60068-2-45	1992
+A1	1993	Immersion in cleaning solvents	+A1	1993
IEC 60068-2-54	2006	Environmental testing - Part 2-54: Tests - Test Ta: Solderability testing of electronic components by the wetting balance method	EN 60068-2-54	2006

### EN 62391-1:2016

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60068-2-58	2015	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution o metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58 f	2015
IEC 60068-2-69	2007	Environmental testing - Part 2: Tests - Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method	EN 60068-2-69	2007
IEC 60068-2-78	2012	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	2013
IEC 60294	2012	Measurement of the dimensions of a cylindrical component with axial terminations	EN 60294	2012
IEC 60617-DB	-	Graphical symbols for diagrams	-	-
IEC 60695-11-5	-	Fire hazard testing - Part 11-5: Test flames - Needle-flame test method - Apparatus, confirmatory test arrangement and guidance	EN 60695-11-5	-
IEC 60717	2012	Method for the determination of the space required by capacitors and resistors with unidirectional terminations	EN 60717	2012
IEC 61193-2	-	Quality assessment systems - Part 2: Selection and use of sampling plans for inspection of electronic components and packages	EN 61193-2	-



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Edition 2.0 2015-10

# INTERNATIONAL STANDARD



Fixed electric double-layer capacitors for use in electric and electronic equipment –

**Part 1: Generic specification** 





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Edition 2.0 2015-10

# INTERNATIONAL STANDARD



Fixed electric double-layer capacitors for use in electric and electronic equipment –

Part 1: Generic specification

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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### INTERNATIONAL ELECTROTECHNICAL COMMISSION

# FIXED ELECTRIC DOUBLE-LAYER CAPACITORS FOR USE IN ELECTRIC AND ELECTRONIC EQUIPMENT –

### Part 1: Generic specification

#### **FOREWORD**

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International Standard IEC 62391-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This second edition cancels and replaces the first edition published in 2006 and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) enhancement of the scope to include electric (high power) application;
- b) implementation of Annex Q, replacing Clause 3 in the first edition;
- c) in addition, minor revisions related to tables, figures and references.

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The text of this standard is based on the following documents:

FDIS	Report on voting
40/2393/FDIS	40/2415/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62391 under the general title *Fixed electric double-layer capacitors for use in electric and electronic equipment* can be found in the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- · reconfirmed.
- · withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

# FIXED ELECTRIC DOUBLE-LAYER CAPACITORS FOR USE IN ELECTRIC AND ELECTRONIC EQUIPMENT -

### Part 1: Generic specification

#### 1 Scope

This part of IEC 62391 applies to fixed electric double-layer capacitors (hereafter referred to as capacitor(s)) mainly used in d.c. circuits of electric and electronic equipment.

This part of IEC 62391 establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications of electronic components for quality assessment or any other purpose.

#### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), Letter symbols to be used in electrical technology

IEC 60050 (all parts), International Electrotechnical Vocabulary

IEC 60062, Marking codes for resistors and capacitors

IEC 60063, Preferred number series for resistors and capacitors

IEC 60068-1:2013, Environmental testing – Part 1: General and guidance

IEC 60068-2-1:2007, Environmental testing – Part 2-1: Tests – Tests A: Cold

IEC 60068-2-2:2007, Environmental testing – Part 2-2: Tests – Tests B: Dry Heat

IEC 60068-2-6:2007, Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)

IEC 60068-2-14:2009, Environmental testing – Part 2-14: Tests – Test N: Change of temperature

IEC 60068-2-20:2008, Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices of with leads

IEC 60068-2-21:2006, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-45:1980, Environmental testing – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents
Amendment 1:1993)

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IEC 60068-2-54:2006, Environmental testing – Part 2-54: Tests – Test Ta: Solderbility testing of electronic components by the wetting balance method

IEC 60068-2-58:2015, Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)

IEC 60068-2-69:2007, Environmental testing – Part 2-69: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method

IEC 60068-2-78:2012, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60294:2012, Measurement of the dimensions of a cylindrical component with axial terminations

IEC 60617 (all parts), Graphical symbols for diagrams

IEC 60695-11-5, Fire hazard testing – Part 11-5: Test flames – Needle-flame test method – Apparatus, confirmatory test arrangement and guidance

IEC 60717:2012, Method for the determination of the space required by capacitors and resistors with unidirectional terminations

IEC 61193-2, Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages

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